TO.: Reference Sheet NO.: A250201



APPROVAL SHEET

MULTILAYER CERAMIC CAPACITOR

Commercial Grade

(Thin Layer Large-Capacitance Type)



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* Notice

This sheet is for reference only and is subject to change or be discontinued without notice. Please contact our sales representatives for detailed information.

	< SPECIFICATION SUMMARY >								
SAMWHA Part no.		CS1608X7R105K160NRB							
Туре		General / Thin Layer Large-Capacitance							
Items	Specification	Unit	Test Conditions						
Capacitance	1.0	μF	Testing Frequency: 1.0 ± 0.1KHz						
Capacitance Tolerance	± 10	%	Testing Voltage : 1.0 ± 0.2 Vrms Should be measured at 25 °C						
Dissipation Factor	Max. 12.5	%							
Insulation Resistance	More than 50	МΩ	Should be measured with a DC voltage not exceeding rated voltage at 25°C for 2 minutes of charging.						
	1.60 ± 0.15	L (mm)	Capacitance Tolerance Codepage 4/14						
Chip Size	0.80 ± 0.10	W (mm)	Chip sizepage 5/14 Characteristics & Test Methodpage 6/14~8/14						
	0.80 ± 0.10	T (mm)							

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PART NO.		SAMWHA SPEC.	CS1608X7R105K160NRB
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NO	REASON	CONTENTS	DATE OF APPROVAL	CHECKED	REMARKS
1	Initial written	full document	96. 03. 27		
2	Re-revision of approval document	full document	25. 02. 01		

General Description

1. General Article

Application Range

These specifications refer to the "Multilayer Ceramic Capacitors" mainly used in various every products such as home appliances, audio/visual equipment, communication devices, and Etc.

*Caution: Industrial equipment / For the high reliability equipment / LED equipment / Etc.

Please contact sales representatives or product engineers before using the products.

(For details, please referenece "Note" page)

2. General Code

(1) Type Designation

100

<u>cs</u>	<u>1608</u>	<u>X7R</u>	<u>105</u>	<u>K</u>	<u>160</u>	<u>N</u>	<u>R</u>	<u>B</u>
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)	(9)

- 1) Multilayer Ceramic Capacitor (Commercial Grade)
- 2) Size Code: This is expressed in tens of a millimeter.

The first two digits are the length, The last two digits are width.

3) Temperautre Coefficient Code

Classification	Code	Temperature Range	Capacitance Tolerance
Class	COG	-55 to +125 ℃	± 30 ppm / ℃
	X5R	-55 to +85℃	± 15 %
	X7R	-55 to +125 ℃	± 15 %
Class II	X7S	-55 to +125 ℃	± 22 %
Class II	X7T	-55 to +125 ℃	+ 22 ~ - 33 %
	X6S	-55 to +105 ℃	± 22 %
	Y5V	-30 to +85℃	+ 22 ~ - 82 %

4) Capacitance Tolerance Code

The nominal Capacitance Value in $\ensuremath{\text{pF}}$ is expressed by three digit numbers.

The first two digits represents significant figures and the last digit denotes the number of zero

ex) 104 = 100000 pF / R denotes decimal / 8R2 = 8.2 pF

5) Capacitance Tolerance Code

Code	В	С	D	F	G	J	K
Tolerance	± 0.1 pF	± 0.25 pF	± 0.5 pF	± 1.0 %	± 2.0 %	± 5.0 %	± 10 %
Code	M	Р	Z	Н	I	U	V

6) Voltage Code

Code	6R3	100	160	250	350	500	101	201	251	501	631	102	202	302
Rate	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC
Voltage	6.3V	10V	16V	25V	35V	50V	100V	200V	250V	500V	630V	1KV	2KV	3KV

7) Termination Code

N: Ni-Sn (Nickel-Tin Plate)

A : Ag/Ni-Sn (Ag Epoxy/Nickel-Tin Plate) → Soft Termination Type

8) Packing Code

R: 7" Reel Type, L: 13" Reel Type, B: Bulk Type

General Description

9) Thickness option

Thickne	ess (mm)	Code	Thickne	ss (mm)	Code	
t	Tolerance (±)	Code	t	Tolerance (±)	Code	
0.30	0.03	Blank	1.30	0.20	E	
0.50	0.05	Blank	1.35	0.20	Н	
0.60	0.10	Α	1.60	0.20	I	
0.80	0.10	В	1.80	0.20	J	
0.85	0.15	В	2.00	0.25	K	
1.00	0.15	E	2.50	0.25	L	
1.10	0.15	E	2.80	0.30	M	
1.15	0.15	E	3.20	0.30	N	
1.25	0.15	E	5.00	0.40	0	

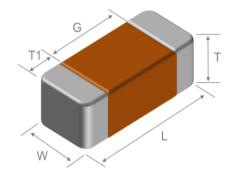
^{*3216} Size ≥ 2.2 µF 100V ⇒ T : Tol±0.30

3. Temperature Characteristics

See Page 8 (Specifications and Test Methods: No.13)

4. Constructions and Dimensions

1) Dimensions



(Unit: mm)

				Dime	ension		
Size Code	EIA Code	Length		Wi	idth	T1(min.)	G(min.)
		L	Tol(±)	W	Tol(±)	1 1(111111.)	G(IIIII.)
0603	0201	0.60	0.03	0.30	0.03	0.05	0.15
1005	0402	1.00	0.05	0.50	0.05	0.15	0.30
1608	0603	1.60	0.15	0.80	0.10	0.20	0.50
2012	0805	2.00	0.20	1.25	0.15	0.20	0.70
3216	1206	3.20	0.30	1.60	0.20	0.30	1.20
3225	1210	3.20	0.40	2.50	0.25	0.30	1.00
4520	1808	4.50	0.40	2.00	0.25	0.30	1.00
4532	1812	4.50	0.40	3.20	0.30	0.30	2.20
5750	2220	5.70	0.50	5.00	0.40	0.30	3.20

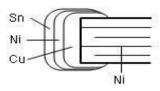
^{*1005} Size \geq 4.7 μ F \Rightarrow L, W, T : Tol±0.15

*1608 Size \geq 10 μ F \Rightarrow W : 0.80±0.15, T : 0.80±0.15

*2012 Size $\geq 10 \mu F \Rightarrow W : 1.25 \pm 0.20, T : 0.85 \pm 0.15$

*3216 Size \geq 47 μ F \Rightarrow W : 1.60±0.30, T : 1.60±0.30

2) Construction of Termination



Spec	cifications	and Tes	t Methods (Thin Layer Large-Capacitance Ty	pe))			(IEC-60	384 Qualifi	ed)
No.	Test	Item	Specification			Test M	lethods an	d Conditio	ons	
1	Operating T Rar		X7R, X7S, X7T : -55 to +125℃ X6S : -55 to +105℃ X5R : -55 to +85℃ Y5V : -30 to +85℃							
2	Insulation I	Resistance	50 Ω.F min	Ci	pplied Voltag harging Time harge/Discha		2r	ated voltage nin. 0mA max.		
3	Voltage	e proof	No defects or abnormalities	Applied Time				250% to 5sec.)mA max.		
4	Capac	itance	within the specified tolerance		easurement ⁻ oplied Voltag			5℃ nown in the t	table	
					Capacita		Frequency		Voltage	
					C≤10µ C>10µ		1 ± 0.1kHz 120 ± 24Hz		0.5~1.0Vrms 0.5 ± 0.1Vrms	
5	Dissipatio	on Factor	12.5% max *3216 Size 100⊭ : 15% max Y5V : 20% max	Ini	itial Measure		Pe ac	erform the in	iitial measure Note1 for Clas	ss II
					Measurement after test Take it out and set it for 24: (Class II) then measure				±2 hours	
6	Solder	ability	95% of the terminations is to be soldered evenly and continuously.	So Im	older older tempera nmersion time re-Heating		24 3 :	6.5Sn-3Ag-0 l5±5°C ± 0.1sec. 0~120°C for		
		Appearance	No defects which may affect performance	Pr (3:	reheat Tempe reheat Time 225,4520,45	32 Size)		20 to 150°C nin.		
			Within ±7.5%		reheat Tempe	erature		00 to 120°C 70 to 200°C		
		Change	Y5V :≦ ±20%		reheat Time oldering Tem	р	1r	nin.	,	
	Resistance to	5	12.5%max		nmersion Tim			60±5°C 0±0.5 sec.		
7	Soldering Heat	Dissipation Factor	*3216 Size 100# : 15% max Y5V : 20% max		itial Measure				iitial measure Note1 for Clas	
		I.R	50 Ω.F min	M	easurement a	after test			n temperature nen measure	for
		Appearance	No defects which may affect performance		eat treatment ycles	ts		nown in the t	table	
		Capacitance Change	Within ±7.5% Y5V : Within ±20%		Step	Min.	2	3 Max.	4	
8	Rapid change of temperature	Dissipation Factor	12.5%max *3216 Size 100⊭ : 15% max Y5V : 20% max		Temp (℃) Time (min)	Operating temp. +0, -3	Room Temp	Operating temp. +3, -0 30 ± 3	Room Temp	
		I.R	50 Ω.F min		itial measure		ac Pe	cording to N	I nitial measure Note1 for Clas nal measurer Note2	ss II

No. Test Item Specification Appearance No defects which may affect performance	Test Methods and Conditions Testing Time 1000+48/-0 hrs
Appearance No defects which may affect performance	Testing Time 1000+48/-0 hrs
	Applied Voltage Rated Voltage x150%
Capacitance Change Within ±12.5% Y5V : Within ±30%	Temperature (C0G,X7R) 125±3℃ Temperature (X5R, Y5V) 85±3℃
9 Endurance Dissipation Factor Pactor Dissipation Factor 20%max *3216 Size 100 #F: 30% max Y5V: 40% max	Charge/discharge current 50mA max. Initial measurement Perform the initial measurement according to Note1 for Class II
I.R 12.5 Ω.F min	Measurement after test Perform the final measurement according to Note2
Support Solder Chip Printed circuit board before	Substrate material Glass Epoxy Board Thickness 1.6mm
Substrate bending test Substrate bending test No cracking or marking defects shall occur	D.8mm (0603/1005size) Bending limit 1mm Pressurizing speed 1mm/sec. Holding time 5±1sec.
Capacitance Change Within ±10% Y5V: Within ±30% Within +30/-40% (cap≥10/#)	
Appearance No defects which may affect performance	After soldering and then let sit for 24±2hr at room temperature
Capacitance Change Whin the specified tolerance	Type of Vibration From 10Hz to 55Hz then 10Hz again Vibration Time 1min. Total Amplitude 1.5mm Vibration directions and time This motion shall be applied for a period 2 hours in each 3 mutually perpendicular
Dissipation Factor 12.5%max *3216 Size 100 /F : 15% max Y5V : 20% max	directions (total is 6hours)
Appearance No defects which may affect performance	Applied Voltage Rated voltage Temperature 40±2°C Humidity 90 to 95%RH Time 500+24/-0 hrs
Capacitance Within ±12.5% Change Y5V : Within ±30%	Time 500+24/-0 hrs Charge/Discharge Current 50mA max. Initial measurement Perform the initial measurement according
damp heat, steady state Dissipation Factor 20%max 20%max 3216 Size 100 / F : 30% max 45V : 40% max	to Note1 for Class II Measurement after test Perform the final measurement according to Note2
I.R 12.5 Ω.F min	

Spec	cifications and Tes	t Method	ds (Thin Layer	oe) (IEC-60384 Qualified)		
No.	Test Item	Specification				Test Methods and Conditions
		Ohan	Torre Bonne	Reference	Occ. Ohanna	
		Char.	Temp. Range	Temp.	Cap. Change	The capacitance change should be measured after 5 min at each specified temperature stage.
13	Temperature characteristic	X5R	-55 to +85°C	25℃	Within ±15%	The ranges of capacitance change compared with the 25℃ value over
	of capacitance	X6S	-55 to +105°C	25℃	Within ±22%	the temperature ranges shown in the table should be within the specified
		X7R	-55 to +125°C	25℃	Within ±15%	ranges.
		X7S	-55 to +125°C	25℃	Within ±22%	
		X7T	-55 to +125°C	25℃	Within +22/-33%	
		Y5V	-30 to +85°C	25℃	Within +22/-82%	

^{*}Note1. Initial Measurement for Class II

Perform a heat treatment at 150+0,-10°C for one hour and then let sit for 24±2 hours at room temperature, then measure

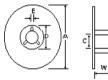
Perform a heat treatment at 150+0,-10°C for one hour and then let sit for 24±2 hours at room temperature, then measure.

^{*}Note2. Measurement after test Class II

[&]quot;Following the International standards, the title of each test item is subject to change."

Packing

- (1) Bulk Packing
 - 1 1000 pcs per polybag
 - ② 5 polybags per inner box
 - 3 10 inner boxes per out box
- (2) Reel Packing
 - ① 8~10 Reels per inner box
 - 2 6 inner boxes per out box
- (3) Reel Dimensions



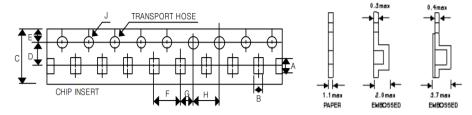
								(Unit : mm)
Mark	Size Code	EIA Code	Α	В	С	D	E	W
7 " Reel	0603~3225	0201~1210	Ф178±2	Ф50Min	Ф13±0.5	Ф21±0.8	2±0.5	10±1.5
/ Reel	4520~4532	1808~1812	Ф180+0,-3	Ф60-0,+1	Ф13±0.2	Ф57-0+1	3±0.2	13±0.5
13 " Reel	1005~3225	0402~1210	Ф330±2	Ф70Min	Ф13±0.5	Ф21±0.8	2±0.5	10±1.5

(4) Number of Package

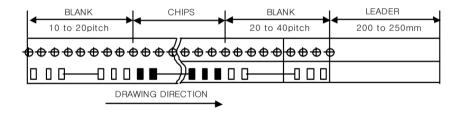
Size Code	EIA Code	7"	13"
Size Code	LIA Code	Quantity (pcs) / Reel	Quantity (pcs) / Reel
CS0603	CC0201	15,000	-
CS1005	CC0402	10,000	50,000
CS1608	CC0603	4,000	15,000
CS2012	CC0805	3,000 ~ 4,000	8,000 ~ 15,000
CS3216	CC1206	2,000 ~ 4,000	6,000 ~ 10,000
CS3225	CC1210	1,000 ~ 3,000	4,000 ~ 10,000
CS4520	CC1808	1,500 ~ 3,000	-
CS4532	CC1812	500 ~ 1,000	1,500 ~ 5,000

Packing

(5) Tape Dimensions

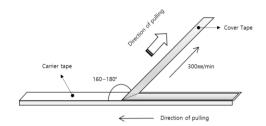


Size Code	EIA Code	Size	Thickness	Α	В	С	D	Е	F	G	Н	J
CS0603	CC0201	0603	all	0.7±0.02	0.4±0.02	8±0.1	3.5±0.05	1.75±0.05	2±0.05	2±0.05	4±0.1	1.55±0.03
CS1005	CC0402	1005	all	1.12±0.03	0.62±0.03	8±0.1	3.5±0.05	1.75±0.05	2±0.05	2±0.05	4±0.1	1.55±0.03
CS1005	CC0402	1005	all	1.12±0.03	0.58±0.03	8±0.1	3.5±0.05	1.75±0.05	2±0.05	2±0.05	4±0.1	1.55±0.03
CS1005	CC0402	1005	all	1.16±0.03	0.66±0.03	8±0.05	3.5±0.05	1.75±0.05	2±0.05	2±0.05	4±0.1	1.55±0.03
CS1608	CC0603	1608	A, B	1.8±0.05	0.95±0.05	8±0.1	3.5±0.05	1.75±0.05	2±0.05	2±0.05	4±0.1	1.55±0.03
CS1608	CC0603	1608	A, B	1.78±0.05	0.92±0.05	8±0.1	3.5±0.05	1.75±0.05	2±0.05	2±0.05	4±0.1	1.55±0.03
CS1608	CC0603	1608	В	1.9±0.05	1.1±0.05	8±0.2	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.1	1.5+0.1
CS1608	CC0603	1608	В	1.9±0.05	1.1±0.05	8±0.1	3.5±0.05	1.75±0.05	4±0.1	2±0.05	4±0.1	1.55±0.03
CS2012	CC0805	2012	Е	2.25±0.1	1.35±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS2012	CC0805	2012	Е	2.4±0.1	1.6±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS2012	CC0805	2012	Е	2.25±0.1	1.35±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.1	1.5+0.1
CS2012	CC0805	2012	Е	2.25±0.05	1.53±0.08	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.1	1.5+0.1
CS2012	CC0805	2012	А	2.3±0.05	1.55±0.05	8±0.1	3.5±0.05	1.75±0.05	4±0.1	2±0.05	4±0.1	1.55±0.03
CS2012	CC0805	2012	В	2.3±0.05	1.55±0.05	8±0.1	3.5±0.05	1.75±0.05	4±0.1	2±0.05	4±0.1	1.55±0.03
CS3216	CC1206	3216	Е	3.5±0.1	1.88±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS3216	CC1206	3216	I	3.45±0.1	1.75±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS3216	CC1206	3216	I	3.7±0.1	1.85±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS3225	CC1210	3225	L	3.58±0.1	2.75±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS3225	CC1210	3225	J	3.58±0.1	2.85±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS3225	CC1210	3225	L	3.5±0.1	2.7±0.1	8±0.1	3.5±0.05	1.75±0.1	4±0.1	2±0.05	4±0.05	1.5±0.1
CS4532	CC1812	4532	М	4.9±0.1	3.6±0.1	12±0.1	5.5±0.05	1.75±0.1	8±0.1	2±0.05	4±0.05	1.5±0.1



(6) Cover tape peel-off Strength

- 1. Peeling strength 10 g.f to 70 g.f
- 2. Measurement Method



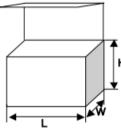
Packing

(7) Packing Label(* Reference image)

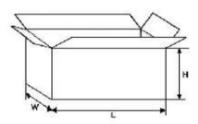


- ① Customer
- 2 Part No.3 Lot No
- ④ Q/ty

(8) Packing Box







Out box drawing

Packing Box Dimensions

(Unit:mm)

Division		Size				
	DIVISION	L	W	Н		
	7 " Reel Box (in 5 reels)	183	65	185		
Inner Box	7 " Reel Box (in 10 reels)	185	135	185		
	13 " Reel Box	330	65	337		
Out Box	7 " Reel Box	430	390	210		
Cut Box	13 " Reel Box	350	350	360		

Caution

▶ Storage Condition

When solderability is considered, capacitor are recommended to be used in 12 months.

MLCC should be stored at 5~40 °C with a relative humidity of 20~70%

High humidity can reduce solderability due to oxidation.

Use the product within 6 months of the outgoing delivery date, and check the packaging if more than 6 months have passed.

It's recommended to use within 1 year to avoid solderability issues from long-term storage.

If over 1 year, verify solderability before use.

▶ The Regulation of Environmental Pollution Materials

Never use materials mentioned below in MLCC products regulated this document.

Pb, Cd, Hg, Cr+6, PBB(Polybrominated biphenyl), PBDE(Polybrominated diphenyl ethers), asbestos

▶ Reflow Soldering

- 1. The sudden temperature change easily causes mechanical damages to ceramic components. Therefore, the preheating procedures should be required for the soldering of ceramic components.
- 2. Please refer to the recommended soldering profiles as shown in figures, and keep the temperature difference (\triangle T) within the range recommended in Table 1.

Table 1

Size code (EIA Code)	Temperature Difference	
0603, 1005, 1608, 2012, 3216	△T≤150°C	
3225 size and over	∆T≤130°C	

Recommended Conditions

Size code (EIA Code)	Lead Free Solder		
Peak Temperature	240 - 260°C		
Atmosphere	Air or N ₂		

^{*} Compliant Standard JESD22

► Standard condition for reflow soldering Temp(°C Peak Temp. (240~260) Liquidous Gradual Temp.(220) Cooling Δ Preheat Temp.(Max 200) Temp.(Min 150) Preheating Time 60~120sec 30~60sec

▶ Flow Soldering

- 1. The sudden temperature change easily causes mechanical damages to ceramic components. Therefore, the preheating procedures should be required for the soldering of ceramic components.
- 2. Please refer to the recommended soldering profiles as shown in figures, and keep the temperature difference (\triangle T) within the range recommended in Table 2.

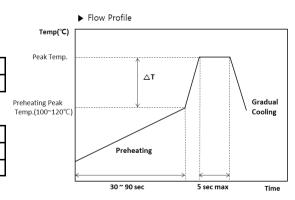
Table 2

<u>- 400.0 E</u>	
Size code	Temperature Difference
1608. 2012. 3216	∧T≤150°C

Recommended Conditions

Conditions	Lead Free Solder
Soldering Peak Temperature	250 - 260°C
Atmosphere	Air or N ₂

*Lead Free Solder : Sn-3.0Ag-0.5Cu



Notice

▶ Land Dimension

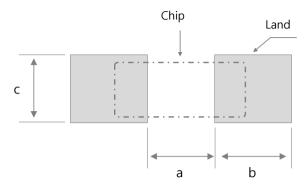


Table . Reflow Soldering Method

Chip size	Chip tol.	a	b	с
[mm]	[mm]	[mm]	[mm]	[mm]
0603	±0.03	0.2~0.25	0.2~0.3	0.25~0.35
0003	±0.05/±0.09	0.23~0.3	0.25~0.35	0.3~0.4
1005	±0.1	0.3~0.5	0.35~0.45	0.4~0.6
	±0.2	0.4~0.6	0.4~0.5	0.5~0.7
1608	±0.1	0.6~0.8	0.6~0.7	0.6~0.8
1606	±0.2	0.7~0.9	0.7~0.8	0.8~1.0
2012	±0.1	0.9~1.3	0.6~0.8	1.2~1.4
2012	±0.2	1.0~1.4	0.6~0.8	1.2~1.4
3216	±0.2	1.8~2.0	0.9~1.2	1.5~1.7
3210	±0.3	1.9~2.1	1.0~1.3	1.7~1.9
3225		2.0~2.4	1.0~1.2	1.8~2.3
4532		3.0~3.5	1.2~1.4	2.3~3.0
5750		4.0~4.6	1.4~1.6	3.5~4.8

^{*}Please confirm the suitable land dimensions, which are determined through the evaluation of the actual SET and PCB

Note

(1) 'Aging'/'De-aging' behavior of high dielectric constant type MLCCs

(Typically represented by X7R temperature characteristic of which main composition is BaTiO₃)

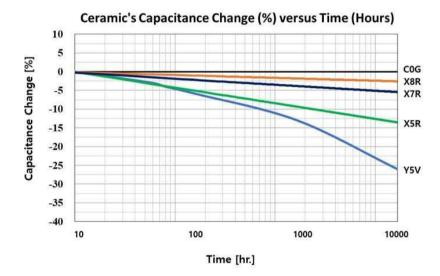
'Aging' / 'De-aging' Behavior of high dielectric MLCCs Please note that high dielectric type dielectric ceramic capacitors have a "normal" 'aging' behavior / characteristic, that is; their capacitance value decreases with time from its value when it was first manufactured. From that date, the capacitance value begins to decrease at a logarithmic rate defined by:

 $Ct = C_{24} (1 - k \log 10 t)$

where,

Ct : Capacitance value, t hours after the start of 'aging C_{24} : Capacitance value, 24 hours after its manufacture k : Aging constant (capacitance decrease per decade-hour)

t: time, in hours, from the start of 'aging'



The capacitance value can be restored (also known as 'de-aged') by exposing the component to elevated temperatures approaching its curie temperature (approximately 120°C). This 'de-aging' can occur during the component's solder-assembly onto the PCB, during life or temperature cycle testing, or by baking at 150°C for about 1 hour.

(2) Caution of Application

Please contact our sales representatives or product engineers before using the products in this catalog for the applications listed below, which require especially high reliability for the prevention of defects which might directly damage a third party's life, body or property, or when one of our products is intended for use in applications other than those specified in this catalog.

- a Aircraft equipment
 b Aerospace equipment
 c Undersea equipment
 d Power plant equipment
 m Medical equipment
 f Transportation equipment (vehicles, trains, ships, etc.)
- Medical equipment
 Transportation equipment (venicles, trains, snips, etc.)
 Traffic signal equipment
 Disaster prevention / crime prevention equipment
- i) Industrial equipment (Conveyors, Robot equipment, etc)i) Led equipment
- Application of similar complexity and/or reliability requirements to the applications listed above